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Responsible committee: EPL/46 Cables, wires and waveguides, radio frequency connectors and accessories for communication and signalling

Interested committees:

Title: BS EN IEC 63185 Measurement of the complex permittivity for low-loss dielectric substrates balanced-type circular disk resonator method

Please notify the secretary if you are aware of any keywords that might assist in classifying or identifying the standard or if the content of this standard

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- iii) requires additional national guidance or information

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Introduction

This draft standard is based on national and international discussions. Your comments on this draft are invited and will assist in the preparation of the consequent standard.

For international standards, comments will be reviewed by the relevant UK national committee before sending the consensus UK vote and comments to the international committee, which will then decide appropriate action. If the international standard is approved, it is usual for the text to be published as a British Standard.

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UK Vote

Please indicate whether you consider the UK should submit a negative (with supporting technical reasons) or positive vote on this draft. Please indicate if you are aware of any reason why this draft standard should not be published as a British Standard.

Submission of Comments

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Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx
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1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex (e.g. 3.1)	Paragraph/Figure/ Table/Note	Type of comment	Commend (justification for change) by the MB	Proposed change by the MB	Secretariat observations on each comment submitted
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	



46F/656/CD

COMMITTEE DRAFT (CD)

PROJECT NUMBER:

IEC 63185 ED2

DATE OF CIRCULATION:

2023-11-17

CLOSING DATE FOR COMMENTS:

2024-02-09

SUPERSEDES DOCUMENTS:

46F/626/RR

IEC SC 46F : RF AND MICROWAVE PASSIVE COMPONENTS

SECRETARIAT:

United States of America

SECRETARY:

Mr John Morelli

OF INTEREST TO THE FOLLOWING COMMITTEES:

PROPOSED HORIZONTAL STANDARD:

☐

Other TC/SCs are requested to indicate their interest, if any, in this CD to the secretary.

FUNCTIONS CONCERNED:

☐ EMC

☐ ENVIRONMENT

☐ QUALITY ASSURANCE

☐ SAFETY

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TITLE:

Measurement of the complex permittivity for low-loss dielectric substrates balanced-type circular disk resonator method

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**MEASUREMENT OF THE COMPLEX PERMITTIVITY
FOR LOW-LOSS DIELECTRIC SUBSTRATES
BALANCED-TYPE CIRCULAR DISK RESONATOR METHOD**

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- International Standard IEC 63185 has been prepared by subcommittee 46F: RF and microwave passive components, of IEC technical committee 46: Cables, wires, waveguides, RF connectors, RF and microwave passive components and accessories.

The text of this standard is based on the following documents:

FDIS	Report on voting
46F/XX/FDIS	46F/XX/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,